

16.5 GHz Wideband NPN Chip - BFR391

Silicon NPN Planar RF Transistor in bare die form

Rev 1.3 15/02/19

Description

NPN transistor in unencapsulated chip form. It is primarily intended for use in RF wideband amplifiers, such as in aerial amplifiers, radar systems, oscilloscopes, spectrum analyzers, etc. The transistor features low intermodulation distortion and high power gain; due to its very high transition frequency, it also has excellent wideband properties and low noise up to high frequencies.

Ordering Information

The following part suffixes apply:

- No suffix MIL-STD-750 /2072 Visual Inspection
- "H" MIL-STD-750 /2072 Visual Inspection+ MIL-PRF-38534 Class H LAT
- "K" MIL-STD-750 /2072 Visual Inspection+ MIL-PRF-38534 Class K LAT

LAT = Lot Acceptance Test.

For further information on LAT process flows see below.

www.siliconsupplies.com\quality\bare-die-lot-qualification

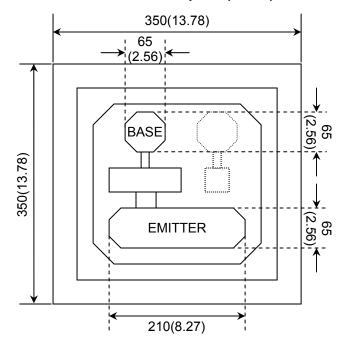
Supply Formats:

- Default Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape By specific request
- Unsawn Wafer By specific request
- With additional electrical selection Specific request
- Sawn as pairs Specific request
- Adjacent pair pick Specific request

Features:

- High Power Gain
- Low Noise
- Wide Transition Frequency

Die Dimensions in µm (mils)



CHIP BACKSIDE IS COLLECTOR

Mechanical Specification

Die Size (Unsawn)	350 x 350 13.78 x 13.78	μm mils	
Base Pad Size	65 x 65 2.65 x 2.65	μm mils	
Emitter Pad Size	210 x 65 8.27 x 65	μm mils	
Die Thickness	150 (±20) 5.90 (±0.78)	μm mils	
Top Metal Composition	Al 0.6μm		
Back Metal Composition	Au 0.6μm		





16.5 GHz Wideband NPN Chip – BFR391

Rev 1.3 15/02/19

Absolute Maximum Ratings T_A = 25°C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN	MAX	UNIT
V_{CBO}	collector-base voltage	open emitter	-	15	V
V_{CEO}	collector-emitter voltage	open base	-	8	V
V_{EBO}	emitter-base voltage	open collector	-	2	V
I _C	DC collector current	-	-	150	mA
P _{tot}	total power dissipation	-	-	400	mW
T_{stg},T_{J}	storage & junction temperature	-	-65	150	°C

Electrical Characteristics T_A = 25°C unless otherwise stated

SYMBOL	PARAMETER	CONDITIONS	MIN	TYP	MAX	SYMBOL
I _{CBO}	collector cut-off current	I _E = 0 ; V _{CB} = 5V	-	_	100	nA
I _{EBO}	emitter cut-off current	$I_{\rm C} = 0$; $V_{\rm EB} = 5V$	-	_	100	nA
h _{FE}	DC current gain	$I_{\rm C}$ = 50mA; $V_{\rm CE}$ = 5V	60	_	150	
f_{T}	transition frequency	$I_C = 50 \text{mA}; V_{CE} = 5V;$ f = 1 GHz	13	16.5	-	GHz
G_P	power gain	$I_C = 50 \text{mA}; V_{CE} = 5V;$ f = 1 GHz	_	17.5	_	dB
NF	noise figure	I_{C} = 10mA; V_{CE} = 1V; f = 1 GHz	-	1.2	1.8	dB

Typical Characteristics T_A = 25°C unless otherwise stated

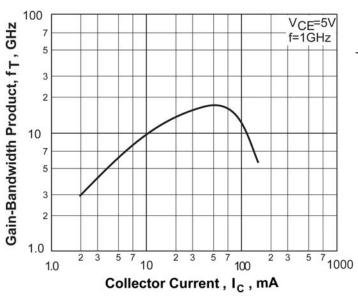


FIGURE 1. Transition Frequency versus Collector Current

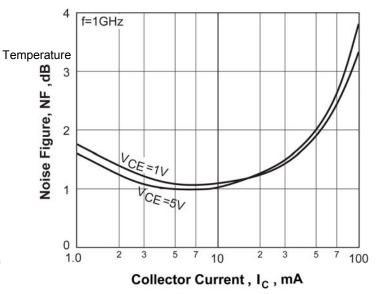


FIGURE 2. Noise Figure versus Collector Current





16.5 GHz Wideband NPN Chip – BFR391

Rev 1.3 15/02/19

Typical Characteristics T_A = 25°C unless otherwise stated

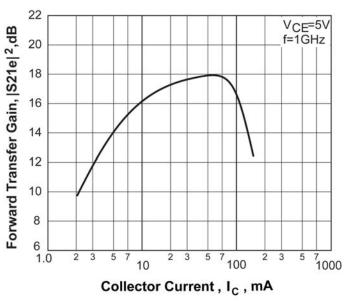


FIGURE 3. Insertion Power Gain versus Collector Current

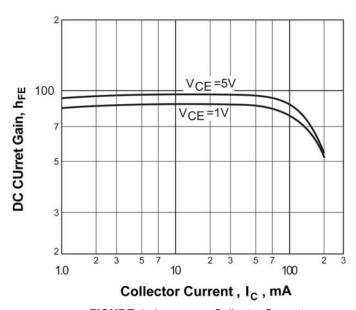


FIGURE 4. h_{FE} versus Collector Current

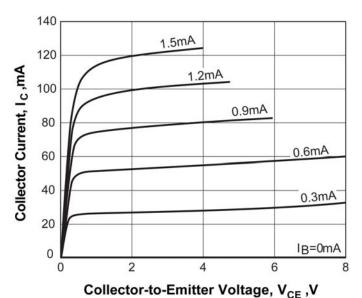


FIGURE 5. Collector Current versus Collector-to-Emitter
Voltage

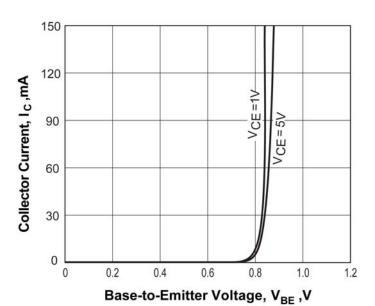


FIGURE 6. Collector Current versus Base-to-Emitter Voltage

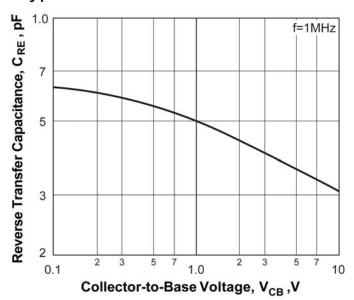




16.5 GHz Wideband NPN Chip — BFR391

Typical Characteristics T_A = 25°C unless otherwise stated

Rev 1.3 15/02/19



Tollector-to-Base Voltage, V_{CB},V

FIGURE 7. Reverse Transfer Capacitance

FIGURE 8. Output Capacitance

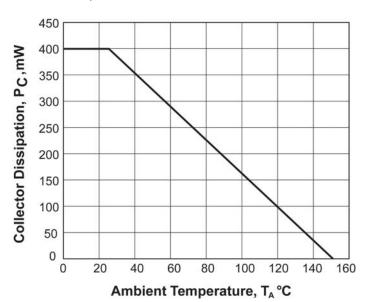


FIGURE 9. Power Dissipation versus Ambient Temperature

DISCLAIMER: The information given in this document shall in no event be regarded as a guarantee of conditions or characteristics. With respect to any examples or hints given herein, any typical values stated herein and/or any information regarding the application of the device, Silicon Supplies Ltd hereby disclaims any and all warranties and liabilities of any kind.

LIFE SUPPORT POLICY: Silicon Supplies Ltd components may be used in life support devices or systems only with the express written approval of Silicon Supplies Ltd, if a failure of such components can reasonably be expected to cause the failure of that life support device or system or to affect the safety or effectiveness of that device or system. Life support devices or systems are intended to be implanted in the human body or to support and/or maintain and sustain and/or protect human life. If they fail, it is reasonable to assume that the health of the user or other persons may be endangered.

